


<b>Search Notes</b>  	<b>Application/Control No.</b>  10577457	<b>Applicant(s)/Patent Under Reexamination</b>  YAMANAKA, TAKAMITSU
	<b>Examiner</b>  Chhaya, Swapneel	<b>Art Unit</b>  2895

SEARCHED			
Class	Subclass	Date	Examiner
257	409,501,506,509,510	12/16/2008	SC
438	212,981,275,770-774,425,297,221	12/16/2008	SC

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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